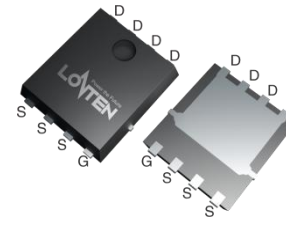
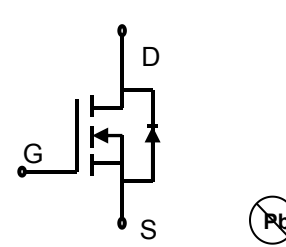


Lonten N-channel 100V, 83A, 8.0mΩ Power MOSFET

Description These N-Channel enhancement mode power field effect transistors are using split gate trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and with stand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications. Features ◆ 100V,83A, $R_{DS(on),max}=8.0m\Omega@V_{GS}=10V$ ◆ Improved dv/dt capability ◆ Fast switching ◆ 100% EAS Guaranteed ◆ Green device available Applications ◆ Motor Drives ◆ UPS ◆ DC-DC Converter	Product Summary <table> <tr> <td>V_{DSS}</td><td>100V</td></tr> <tr> <td>$R_{DS(on),max}@V_{GS}=10V$</td><td>8.0mΩ</td></tr> <tr> <td>I_D</td><td>83A</td></tr> </table> Pin Configuration  DFN5×6  N-Channel MOSFET	V_{DSS}	100V	$R_{DS(on),max}@V_{GS}=10V$	8.0mΩ	I_D	83A
V_{DSS}	100V						
$R_{DS(on),max}@V_{GS}=10V$	8.0mΩ						
I_D	83A						

Absolute Maximum Ratings $T_C = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	100	V
Continuous drain current ($T_C = 25^\circ C$)	I_D	83	A
Continuous drain current ($T_C = 100^\circ C$)		52	A
Pulsed drain current ¹⁾	I_{DM}	332	A
Gate-Source voltage	V_{GSS}	± 20	V
Avalanche energy ²⁾	E_{AS}	132	mJ
Power Dissipation ($T_C = 25^\circ C$)	P_D	100	W
Storage Temperature Range	T_{STG}	-55 to +150	$^\circ C$
Operating Junction Temperature Range	T_J	-55 to +150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.25	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	55	$^\circ C/W$

Package Marking and Ordering Information

Device	Device Package	Marking
LSGN10R080	DFN5X6	LSGN10R080

Electrical Characteristics
 $T_J = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV _{DSS}	V _{GS} =0 V, I _D =250uA	100	---	---	V
Gate threshold voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250uA	2	3	4	V
Drain-source leakage current	I _{DSS}	V _{DS} =100 V, V _{GS} =0V, T _J = 25°C	---	---	1	μA
Gate leakage current, Forward	I _{GSSF}	V _{GS} =20 V, V _{DS} =0 V	---	---	100	nA
Gate leakage current, Reverse	I _{GSSR}	V _{GS} =-20 V, V _{DS} =0 V	---	---	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =30 A	---	7.1	8.0	mΩ
Forward transconductance	g _{fs}	V _{DS} =5V , I _D =30A	---	65	---	S
Dynamic characteristics						
Input capacitance	C _{iss}	V _{DS} = 50 V, V _{GS} = 0 V, F = 1MHz	---	1895	---	pF
Output capacitance	C _{oss}		---	572.5	---	
Reverse transfer capacitance	C _{rss}		---	11.8	---	
Turn-on delay time	t _{d(on)}	V _{DD} = 50V,V _{GS} =10V, I _D = 30A	---	16.6	---	ns
Rise time	t _r		---	20	---	
Turn-off delay time	t _{d(off)}		---	68	---	
Fall time	t _f		---	20.8	---	
Gate resistance	R _g	V _{GS} =0V, V _{DS} =0V, F=1MHz	---	1.7	---	Ω
Gate charge characteristics						
Gate to source charge	Q _{gs}	V _{DS} =50 V, I _D =50A, V _{GS} = 10 V	---	10	---	nC
Gate to drain charge	Q _{gd}		---	4.2	---	
Gate charge total	Q _g		---	28.3	---	
Drain-Source diode characteristics and Maximum Ratings						
Continuous Source Current	I _S		---	---	83	A
Pulsed Source Current ³⁾	I _{SM}		---	---	332	A
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _S =30A, T _J =25°C	---	0.9	---	V
Reverse Recovery Time	t _{rr}	I _S =30A, di/dt=100A/us,	---	50	---	ns
Reverse Recovery Charge	Q _{rr}	T _J =25°C	---	72	---	nC

Notes:

1: Repetitive Rating: Pulse width limited by maximum junction temperature.

2: $V_{DD}=50\text{ V}, V_{GS}=10\text{ V}, L=0.5\text{ mH}, I_{AS}=23\text{ A}, R_G=25\Omega$, Starting $T_J=25^\circ\text{C}$.

3: Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.

Electrical Characteristics Diagrams

Figure 1. On-Region Characteristics

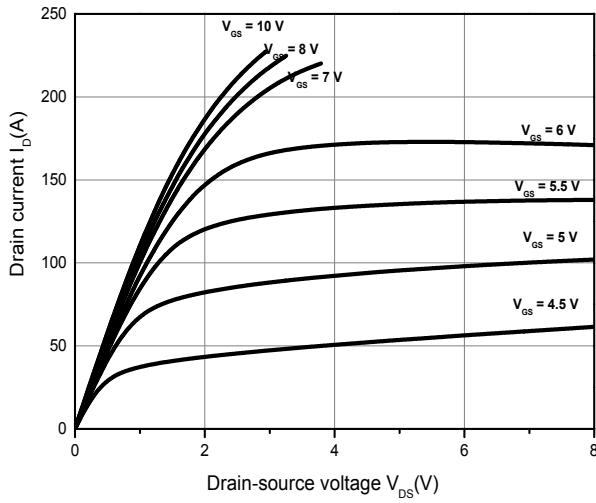


Figure 2. Transfer Characteristics

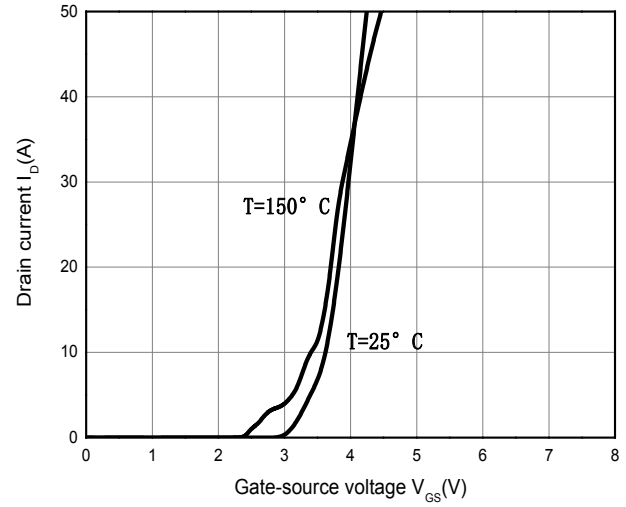


Figure 3. Body-Diode Characteristics

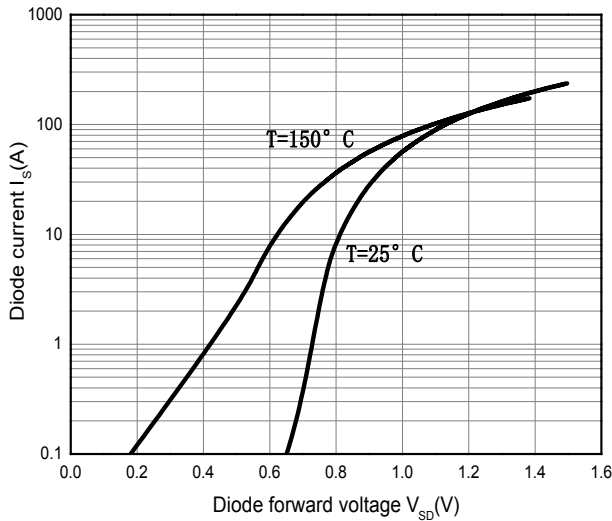


Figure 4. On-Resistance Variation vs. Drain Current

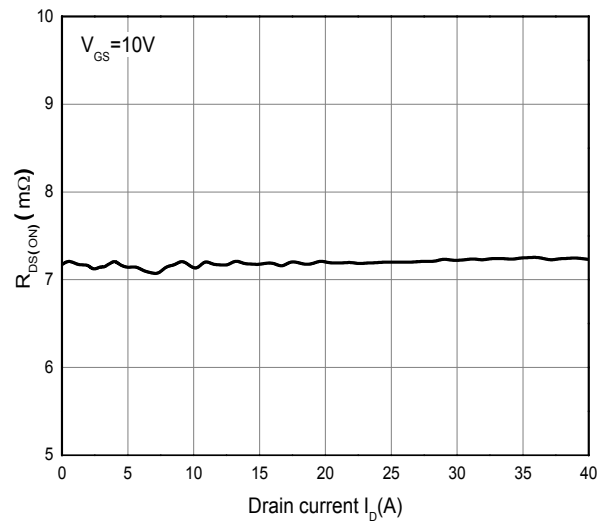


Figure 5. $R_{DS(on)}$ vs. Gate Voltage

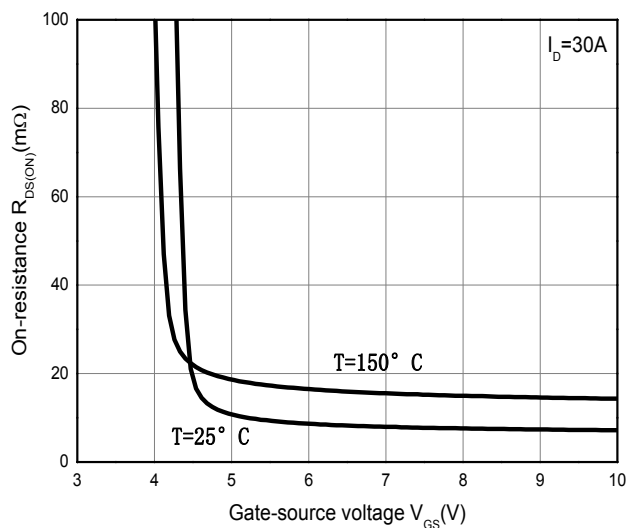


Figure 6. On-Resistance vs. Temperature

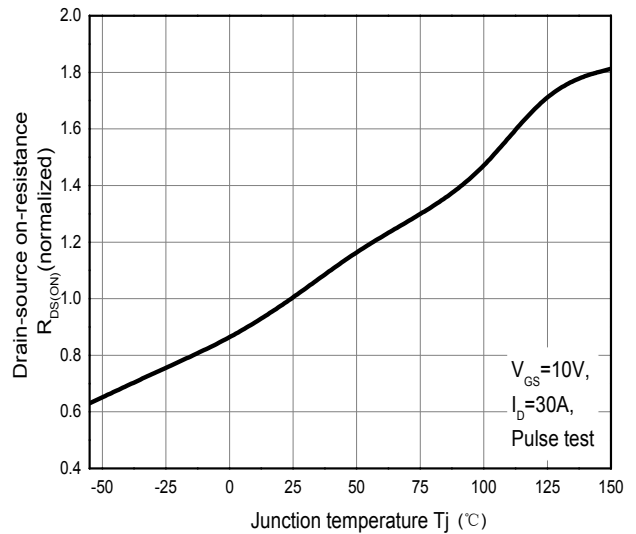


Figure 7. Threshold Voltage vs. Temperature

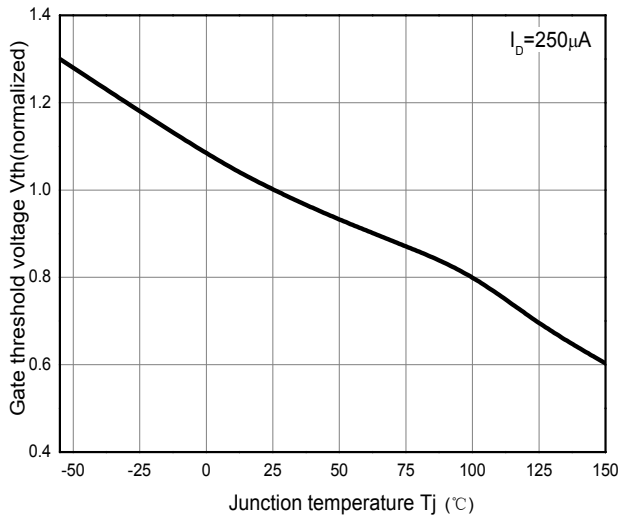


Figure 8. Breakdown Voltage vs. Temperature

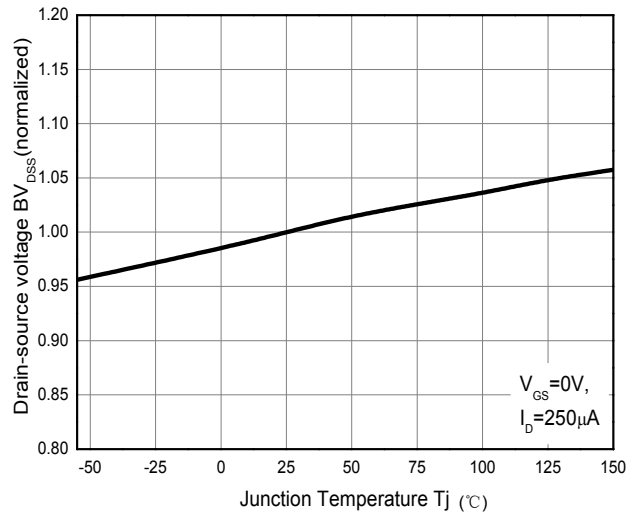


Figure 9. Capacitance Characteristics

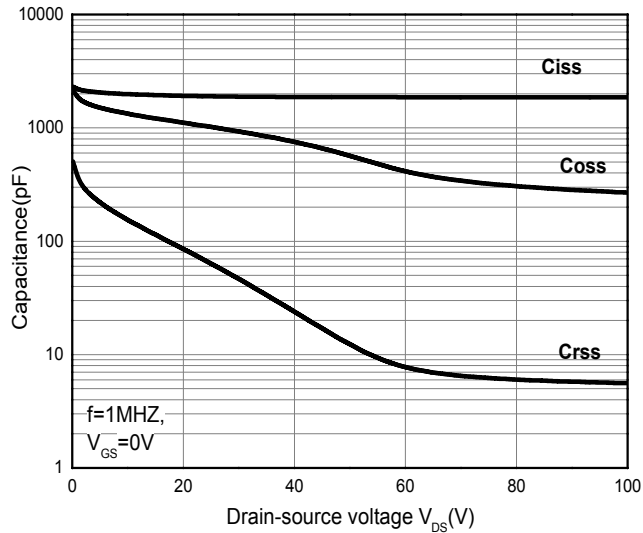


Figure 10. Gate Charge Characteristics

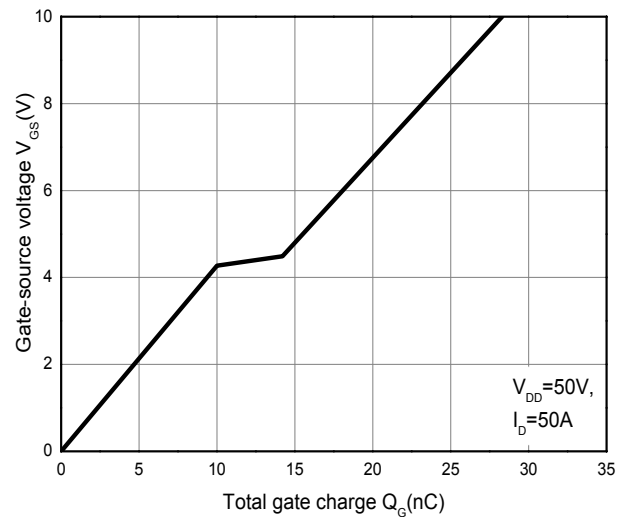


Figure 11. Drain Current Derating

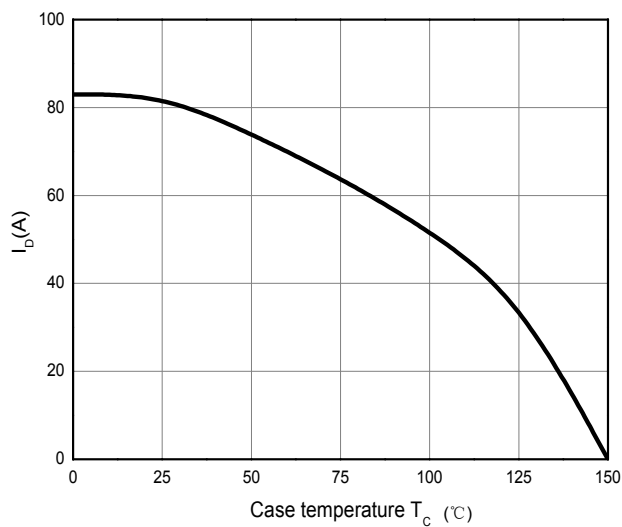


Figure 12. Power Dissipation vs. Temperature

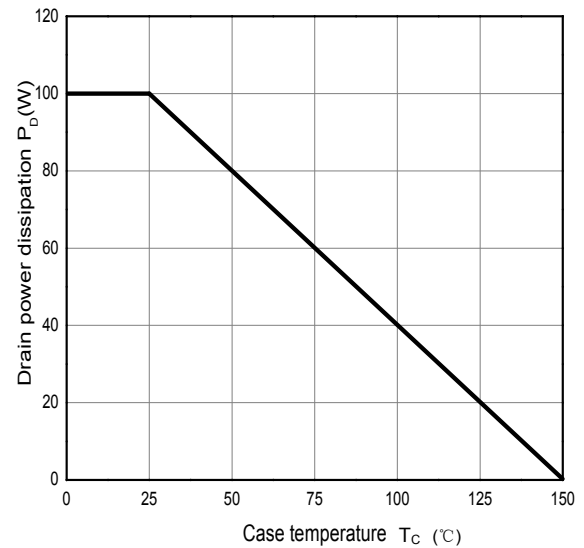


Figure 13. Maximum Safe Operating Area

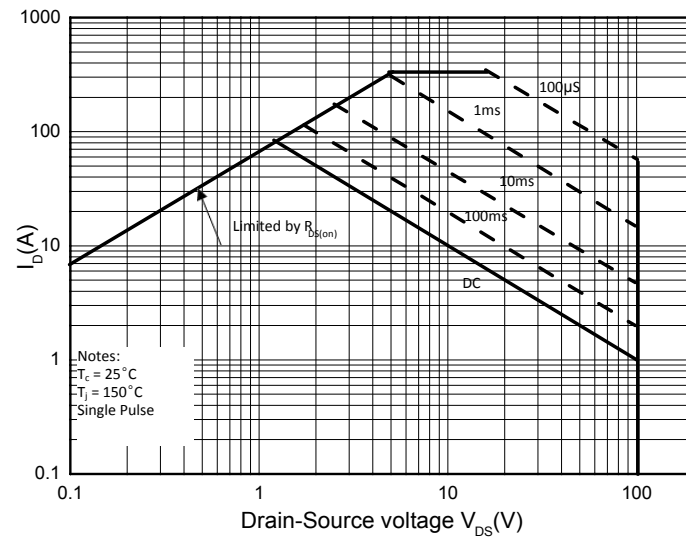
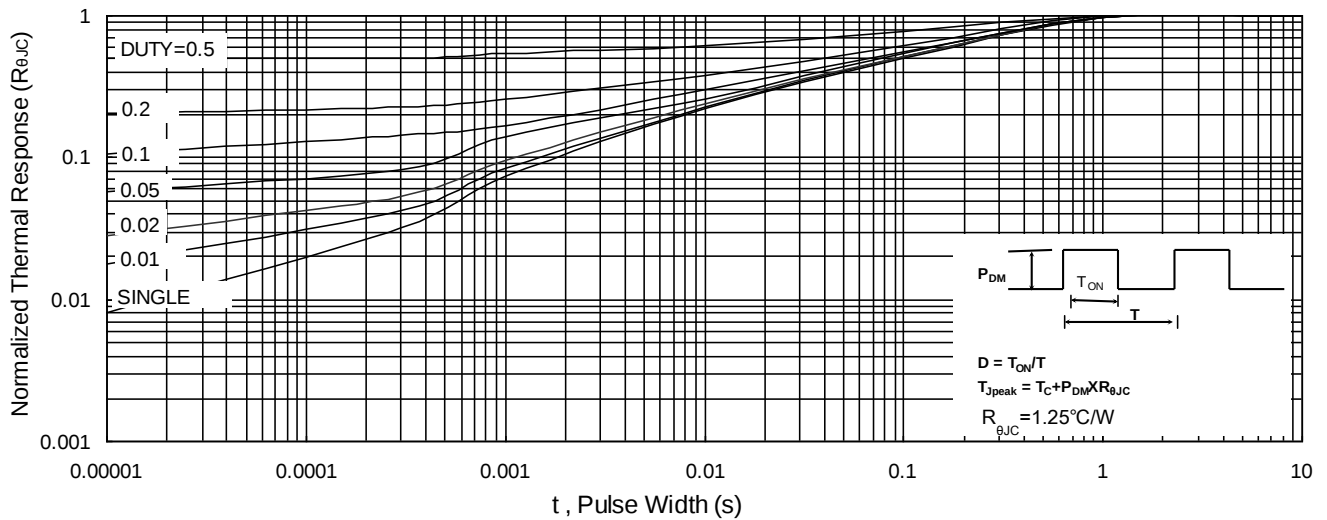


Figure 14. Normalized Maximum Transient Thermal Impedance (R_{thJC})



Test Circuit & Waveform

Figure 15. Gate Charge Test Circuit & Waveform

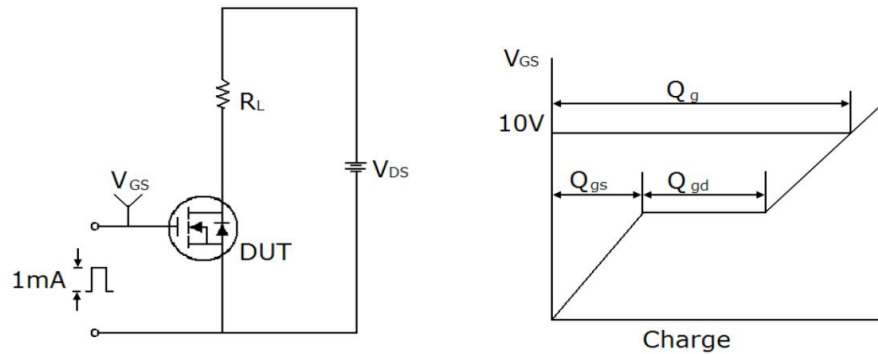


Figure 16. Resistive Switching Test Circuit & Waveform

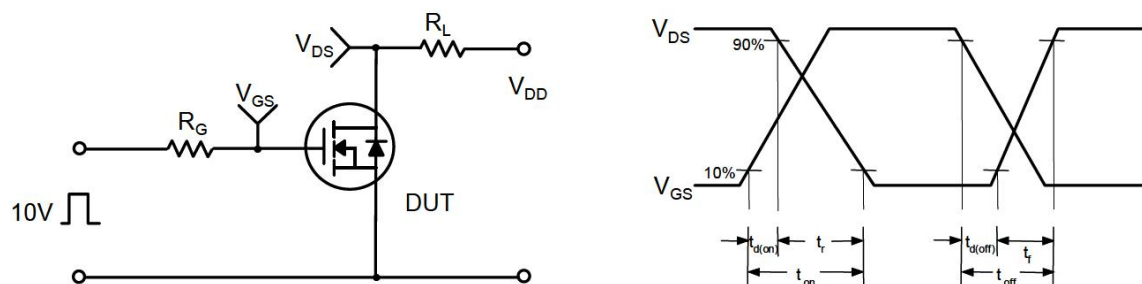


Figure 17. Unclamped Inductive Switching (UIS) Test Circuit & Waveform

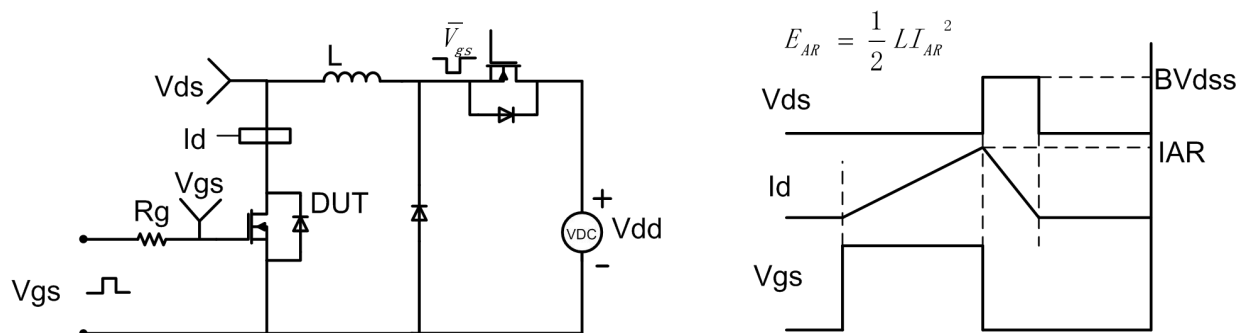
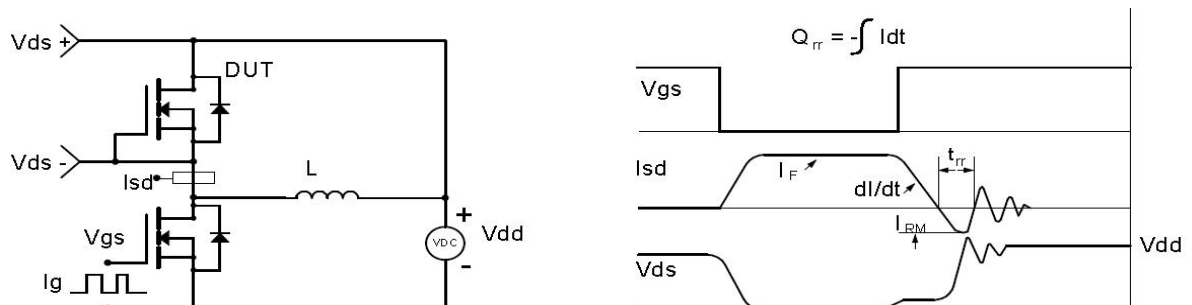
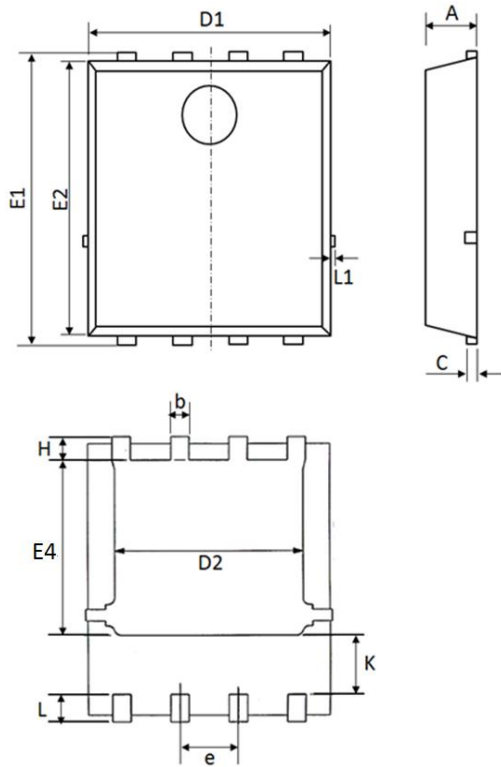


Figure 18. Diode Recovery Circuit & Waveform

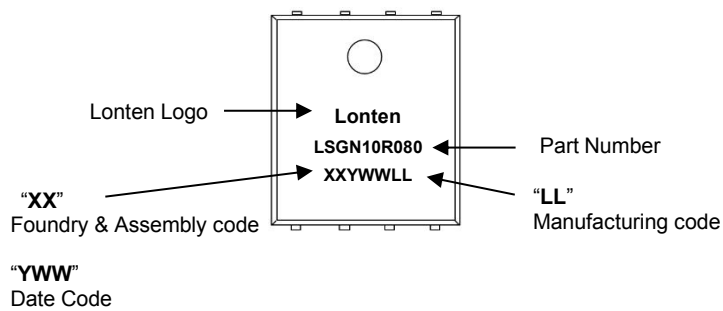


Mechanical Dimensions for DFN5×6



COMMON DIMENSIONS						
SYMBOL	MILLIMETERS			INCHS		
	MIN	NOM	MAX	MIN	NOM	MAX
A	1	1.1	1.2	0.039	0.043	0.047
b	0.3	0.4	0.5	0.012	0.016	0.020
C	0.154	0.254	0.354	0.006	0.010	0.014
D1	5	5.2	5.4	0.197	0.205	0.213
D2	3.8	4.1	4.25	0.150	0.161	0.167
E1	5.95	6.15	6.35	0.234	0.242	0.250
E2	5.66	5.86	6.06	0.223	0.231	0.239
E4	3.52	3.72	3.92	0.139	0.146	0.154
e	1.27 BSC			0.050 BSC		
H	0.4	0.5	0.6	0.016	0.020	0.024
L	0.5	0.6	0.7	0.020	0.024	0.028
L1	-	-	0.12	-	-	0.005
K	1.14	1.29	1.44	0.045	0.051	0.057

DFN5×6 Part Marking Information



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